

08/18/2008

RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2624

PATENT APPLICATION
Docket No.: 2522-047
Client Ref. No. AW8085US/EK

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Deok-Yong KIM et al.

Serial No.: 10/749,670

Examiner: Rosario, Dennis

Filed: December 30, 2003

Art Unit: 2624

Confirmation No.: 9761

For: METHOD AND APPARATUS FOR DETECTING DEFECTS ON A
WAFER

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL REJECTION UNDER 37 CFR 1.116

Responsive to the Final Office Action, Paper No. 20080512, dated May 20, 2008, please amend the application as follows.

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks/Arguments** begin on page 7 of this paper.